EE 3329 - Electronic Devices Syllabus

EE 3329 – Electronic Devices Syllabus ("Extended Play")

The University of Texas at El Paso

The following concepts can be part of the syllabus for the Electronic Devices (EE 3329) course. Note that the list of topics cannot be covered in a semester, it is up to the individual instructors to choose what concepts they wish to cover.

I. Introduction to Quantum Mechanics

- * Principles of Quantum Mechanics
 - Energy Quanta
 - Wave-Particle Duality
 - The Uncertainty Principle
- * Schrödinger's Wave Equation
 - The Wave Equation
 - Physical Meaning of the Wave Function
 - Boundary Conditions
- * Applications of Schrödinger's Wave Equation
 - Electron in Free Space
 - The Infinite Potential Well
 - The Step Potential Function
 - The Potential Barrier

II. Introduction to the Quantum Theory of Solids

* Allowed and Forbidden Energy Bands

- Formation of Energy Bands
- The Kronig-Penney Model
- The k-Space Diagram
- * Electrical Conduction in Solids
 - The Energy Band and the Bond Model
 - Drift Current
 - Electron Effective Mass
 - Concept of the Hole

• Metals, Insulators, and Semiconductors

III. Metal-Semiconductor and Semiconductor Heterojunctions

- * Heterojunctions
 - Heterojunction Materials
 - Energy-Band Diagrams
 - Two-Dimensional Electron Gas
 - Equilibrium Electrostatics
 - Current-Voltage Characteristics

IV. Semiconductors: A General Introduction

* General Material Properties

- <u>Composition</u>
- Purity
- <u>Structure</u>

* Crystal Structure

- The Unit Cell Concept
- Simple 3-D Unit Cells
- Semiconductor Lattices
- Miller Indices
- * Crystal Growth
 - Obtaining Ultrapure Si
 - Single-Crystal Formation
- * Summary

V. Carrier Modeling

- * Semiconductor Models
 - Bonding Model
 - Energy Band Model
 - Carriers
 - Band Gap Energy and Material Classification
- * Carrier Properties

- Charge
- Effective Mass
- Carrier Numbers in Intrinsic Material
- Manipulation of Carrier Numbers Doping
- Carrier-Related Terminology
- * State and Carrier Distributions
 - Density of States
 - The Fermi Function
 - Equilibrium Distribution of Carriers
- * Equilibrium Carrier Concentrations
 - Formulas for *n* and *p*
 - Alternative Expressions for *n* and *p*
 - *n*_i and *np* Product
 - Charge Neutrality Relationship
 - Carrier Concentration Calculations
 - Determination of E_F
 - Carrier Concentration Temperature Dependence

VI. Carrier Action

* <u>Drift</u>

- Definition Visualization
- Drift Current
- Mobility and Scattering
- Resistivity
- Band Bending

* Diffusion

- Definition Visualization
- Hot-Point Probe Measurement
- Diffusion and Total Currents Diffusion Currents Total Currents
- Relating Diffusion Coefficients/Mobilities Constancy of the Fermi Leve Current Flow Under Equilibrium Conditions Einstein Relationship
- * Recombination Generation

- Definition Visualization Band-to-Band Recombination R-G Center Recombination Auger Recombination Generation Process
- * Equations of State
 - <u>Continuity Equations</u>
 - <u>Minority Carrier Diffusion Equations</u>
 - Simplifications and Solutions
 - Problem Solving Sample Problem No. 1 Sample Problem No. 2
- * Supplemental Concepts
 - Diffusion Lengths
 - Quasi-Fermi Levels

VII. pn Junction Electrostatics

* Quantitative Electrostatic Relationships

- Assumptions/Definitions
- Step Junction with $V_A = 0$ Solution for p Solution for E Solution for V Solution for x_n and x_p
- Step Junction with \dot{V}_A ? 0
- Examination/Extrapolation of Results
- Linearly Graded Junctions

VIII. pn Junction Diode: I-V Characteristics

* The Ideal Diode Equation

- Qualitative Derivation
- Quantitative Solution Strategy General Considerations Quasineutral Regional Considerations Depletion Region Considerations Boundary Conditions "Game Plan" Summary

- * Derivation from the Ideal
 - Ideal Theory Versus Experiment
 - Reverse-Bias Breakdown Avalanching Zener Process
 - The R-G Current
 - V_A -> V_{bi} High-Current Phenomena Series Resistance High-Level Injection

IX. BJT Fundamentals

- * Electrostatics
- * Introductory Operational Considerations
- * Performance Parameters
 - Emitter Efficiency
 - Base Transport Factor
 - Common Base d.c. Current Gain
 - Common Emitter d.c. Current Gain

X. BJT Static Characteristics

* Ideal Transistor analysis

- Solution Strategy Basic Assumptions Notation Diffusion Equations/Boundary Conditions Computational Relationships
- General Solution (W Arbitrary) Emitter/Collector Region Solutions Base Region Solution Performance Parameters/Terminal Currents
- Simplified Relationships
 ?p_B(x) in the Base
 Performance Parameters
- Ebers Moll Equations and Model
- * Deviations from the Ideal
 - Ideal Theory/Experiment Comparison
 - Base Width Modulation
 - Punch-Through

- Avalanche Multiplication and Breakdown Common Base Common Emitter
- Geometrical effects Emitter Area ? Collector Area Series Resistances Current Crowding
- Recombination Generation Current
- Graded Base
- Figure of Merit

XI. MOS Fundamentals

* Ideal Structure Definition

- * Electrostatics Mostly Qualitative
 - Visualization Aids Energy Band Diagram Block Charge Diagrams
 - Effect of an Applied Bias General Observations Specific Biasing Regions
- * Electrostatics Quantitative Formulation
 - Semiconductor Electrostatics Preparatory Considerations Delta-Depletion Solution
 - Gate Voltage Relationship
- * Capacitance Voltage Characteristics
 - Theory and Analysis Qualitative Theory Delta – Depletion Analysis
 - Computations and Observations Exact Computations Practical Observations

XII. MOSFETs – The Essentials

- * Qualitative Theory of Operation
- * Quantitative $I_D V_D$ Relationships
 - Preliminary Considerations

Threshold Voltage Effective Mobility

- Square-Law Theory
- Bulk-Charge Theory
- Charge-Sheet and Exact-Charge Theories

XIII. Nonideal MOS

- * Metal-Semiconductor Workfunction Difference
- * Oxide Charges
 - General Information
 - Mobile lons
 - The Fixed Charge
 - Interfacial Traps
 - Induced Charges Radiation Effects Negative-Bias Instability
 - ?V_G Summary
- * MOSFET Threshold Considerations
 - V_T Relationships
 - Threshold, Terminology, and Technology
 - Threshold Adjustment
 - Back Biasing
 - Threshold Summary